## Notice of References Cited Application/Control No. 10/716,457 Examiner Ryan Gleitz Applicant(s)/Patent Under Reexamination YON ET AL. Page 1 of 1

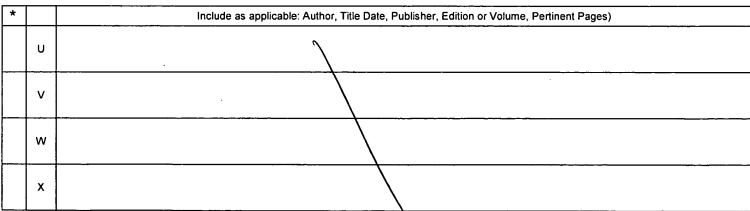
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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